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Artificial Intelligence in Mechanical Engineering: From Statistical Learning to Generative Models

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Message from the Guest Editors

The Special Issue "Artificial Intelligence in Mechanical Engineering: From Statistical Learning to Generative Models" covers the advancements in artificial intelligence in the field of mechanical engineering, tracing its development from statistical learning discriminative and regression models to generative models. This Special Issue encompasses a broad spectrum of AI applications, such as robotics, automation, predictive maintenance, optimization of manufacturing processes, advanced materials design, machine design, structural integrity, damage identification, and evolution and fatigue life estimation.

Topics in this Special Issue of Serious Games include, but are not limited to:

- artificial intelligence
- mechanical engineering
- intelligent fault diagnosis
- robotics
- machine learning
- machine design
- material design
- fatigue damage
- deep learning
- generative Al
- manufacturing
- industry
- feature extraction
- sensors
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Message from the Editor-in-Chief

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